



Open AFM/SPM Meeting



2019 NanoScientific Forum Europe

Scanning Probe Microscopy (SPM)

11-13 September, 2019
University of Bologna, Italy

Certificate of Attendance

presented to

SEYEDMASOOD NIKKHAH

for attending the

2nd NanoScientific Forum Europe NSFE 2019

organized by

University of Bologna, CNR-ISMN Bologna
and

Park Systems Europe

on 11 - 13 September 2019 at the University of Bologna

The conference included lectures and hands-on-sessions on the topics:

Lectures: Organic Interfaces and Semiconductors, Photovoltaic Technologies, New Frontiers in SPM Methodology, Life Science and Biotechnology, Characterization of Novel Semiconducting Materials with Scanning Probe Microscopy

Hands-on-Sessions: Nanomechanical imaging (PinPoint), Liquid Environment, Advanced Piezoelectric Force Microscopy, Kelvin Probe Force Microscopy

Signature

Date 18 September, 2019